



	From	To	
Product marking change	Line1:64 Line2:01 Line3:M Where: M single digit month code	Line1:64 Line2:01 Line3:MI Where: M single digit month code + vertical line corresponding site code	
Reason / Motivation for Change:	- Second sourcing for DFN 12 3*1.35 mm which includes automotive SNUF6401MNT1G.		
Anticipated impact on fit, form, function, reliability, product safety or manufacturability:	The device has been qualified and validated based on the same Product Specification. The device has successfully passed the qualification tests. Potential impacts can be identified, but due to testing performed by ON Semiconductor in relation to the PCN, associated risks are verified and excluded. No anticipated impacts.		
Sites Affected:	ON Semiconductor Sites: ON Seremban, Malaysia ON Tarlac City, Philippines	External Foundry/Subcon Sites: None	
Marking of Parts/ Traceability of Change:	Additional vertical line on month date code (MI) for OSPI Tarlac bui		
Reliability Data Summary:			
QV DEVICE NAME: SNUF6401MNT1G PACKAGE: DFN12 3.0x1.35, 0.5P			
Test	Specification	Condition	Interval
HTRB	JESD22-A108	Tj = Max rate Tj for device, bias = 100% of rated V (for automotive)	2016 hrs
HTSL	JESD22-A103	Ta =Max rate storage temp for device for 1008 hrs	1008 hrs
IOL	MIL-STD-750 (M1037) AEC-Q101	Ta=+25°C, deltaTj=100°C max, Ton=Toff is pkg dependent	15000 cyc
TC	JESD22-A104	Temp = -55°C to +150°C; for 1000 cycles	2000 cyc
HAST	JESD22-A110	Temp = 130C, 85% RH, ~ 18.8 psig, bias = 80% of rated V or 100V max	96 hrs
uHAST	JESD22-A118	Temp = 130C, RH=85%, ~ 18.8 psig	96 hrs
PC	J-STD-020 JESD-A113	IR reflow at 245C or 260C (pkg dependant)	
RSH	JESD22- B106	Ta=265C 10 sec dwell B106	
Electrical Characteristic Summary:			
Available upon request			
List of Affected Parts:			
Current Part Number	New Part Number	Qualification Vehicle	
SNUF6401MNT1G	SNUF6401MNT1G	SNUF6401MNT1G	



Appendix A: Changed Products

Product	Customer Part Number	New Part Number	Qualification Vehicle
SNUF6401MNT1G		NA	SNUF6401MNT1G